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IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re the Application of: Kenji WATANABE et al.

Group Art Unit:

Serial Number: 10/543,151

Examiner:

Filed: July 25, 2005

Confirmation Number:

For:

MAPPING-PROJECTION-TYPE ELECTRON BEAM APPARATUS FOR

INSPECTING SAMPLE BY USING ELECTRONS EMITTED FROM THE

SAMPLE

Attorney Docket Number:

052886

Customer Number:

38834

INFORMATION DISCLOSURE STATEMENT UNDER 37 C.F.R. §1.97(b)

Commissioner for Patents P. O. Box 1450 Alexandria, VA 22313-1450 December 23, 2005

Sir:

In compliance with 37 C.F.R. §1.56, Applicants direct the attention of the Patent and Trademark Office to the documents listed on the attached PTO/SB/08. This paper is being filed within the time periods set forth in 37 C.F.R. §1.97(b). A copy of each non-U.S. document is enclosed herewith.

The inventor considers Japanese Laid-open No. Hei 4-242060 to disclose a reflection election microscope having a similar electron beam deflection device.

If there are any fees due in connection with the filing of this paper, please charge Deposit Account No. 50-2866.

Respectfully submitted,

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SGA/arf

Enclosures:

PTO/SB/08

3 Documents

Combined Form PTO/S	D/00 A P.D			Complete if Known			
Combined Form P10/S	D/U8A&B			Application Number	10/543,151		
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				Examiner Name			
Sheet	1	of	1	Attorney Docket Number	052886		

U.S. PATENT DOCUMENTS							
Examiner Initials*	Cite No.1	Document Number		Publication Date			
		Number	Kind Code ² (if known)	MM-DD-YYYY	Name of Patentee or Applicant of Cited Document		
	1	US 5,576,833		11/19/1996	Miyoshi et al.		
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FOREIGN PATENT DOCUMENTS							
Examiner Initials*	Cite No. ¹	Foreign Patent Document			Publication Date	Name of Patentee or	m
		Country Code ³	Number ⁴	Kind Code ⁵ (if known)	MM-DD-YYYY	Applicant of Cited Document	Translation ⁶
	2	JР	4-242060		08/28/1992		
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NON PATENT LITERATURE DOCUMENTS							
Examiner Initials*	Cite No.1	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city, and/or country where published.					
	3	K. Tsuno, "Simulation of a Wien filter as beam separator in a low energy electron microscope", pp. 127-140, Ultramicroscopy 55 (1994).					
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Examiner Signature		_Da	ate Considered		

^{*}EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

¹Applicant's unique citation designation number (optional). ²See Kind Codes of USPTO Patent Documents at www.uspto.gov, MPEP 901.04 or in the comment box of this document. ³ Enter Office that issued the document, by the two-letter code (WIPO Standard ST. 3). ⁴For Japanese patent documents, the indication of the year of the reign of the Emperor must precede the serial number of the patent document. ⁵Kind of document by the appropriate symbols as indicated on the document under WIPO Standard ST. 16 if possible. ⁶ Applicant is to indicate here if English language Translation is attached.